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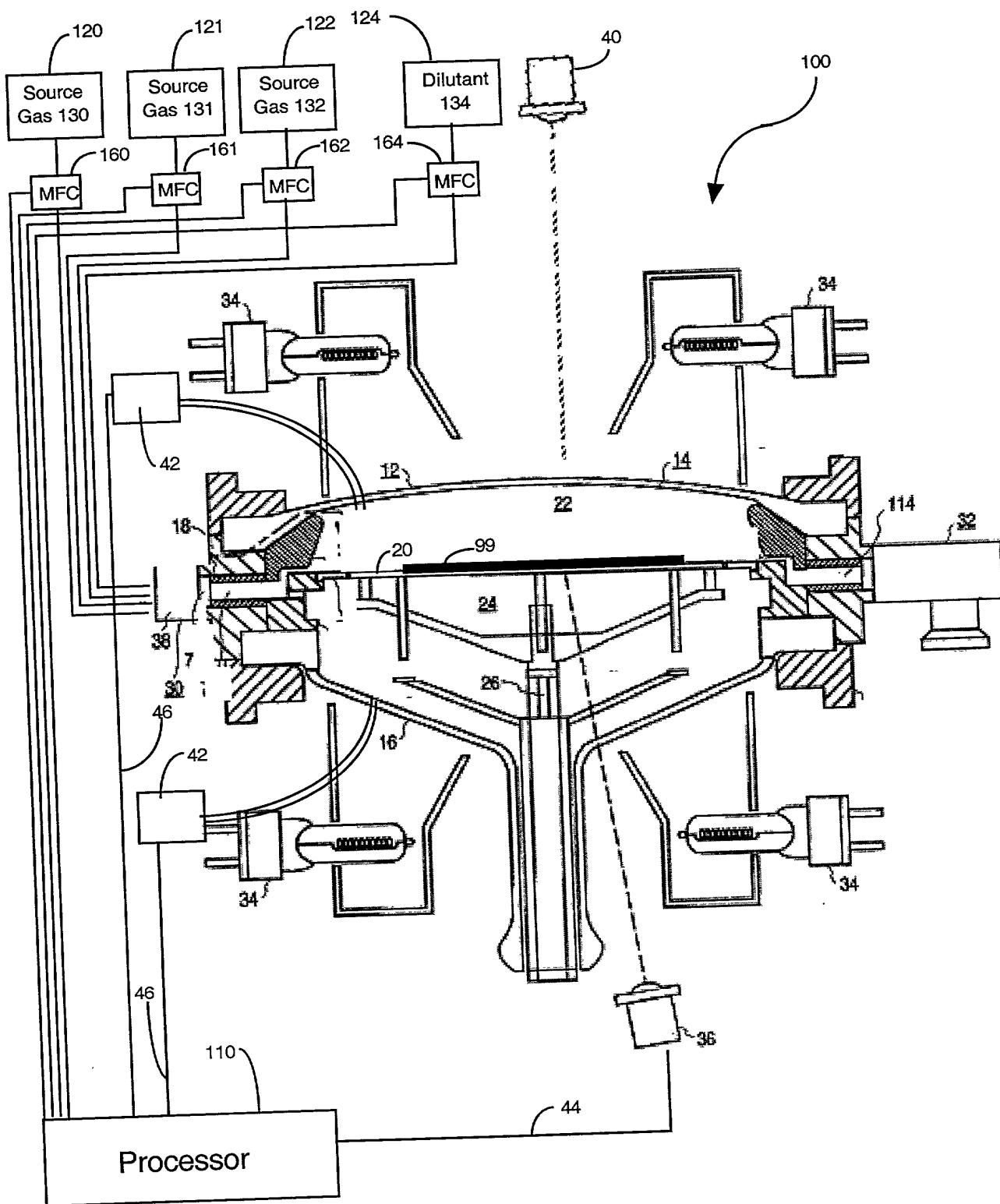


Figure 1

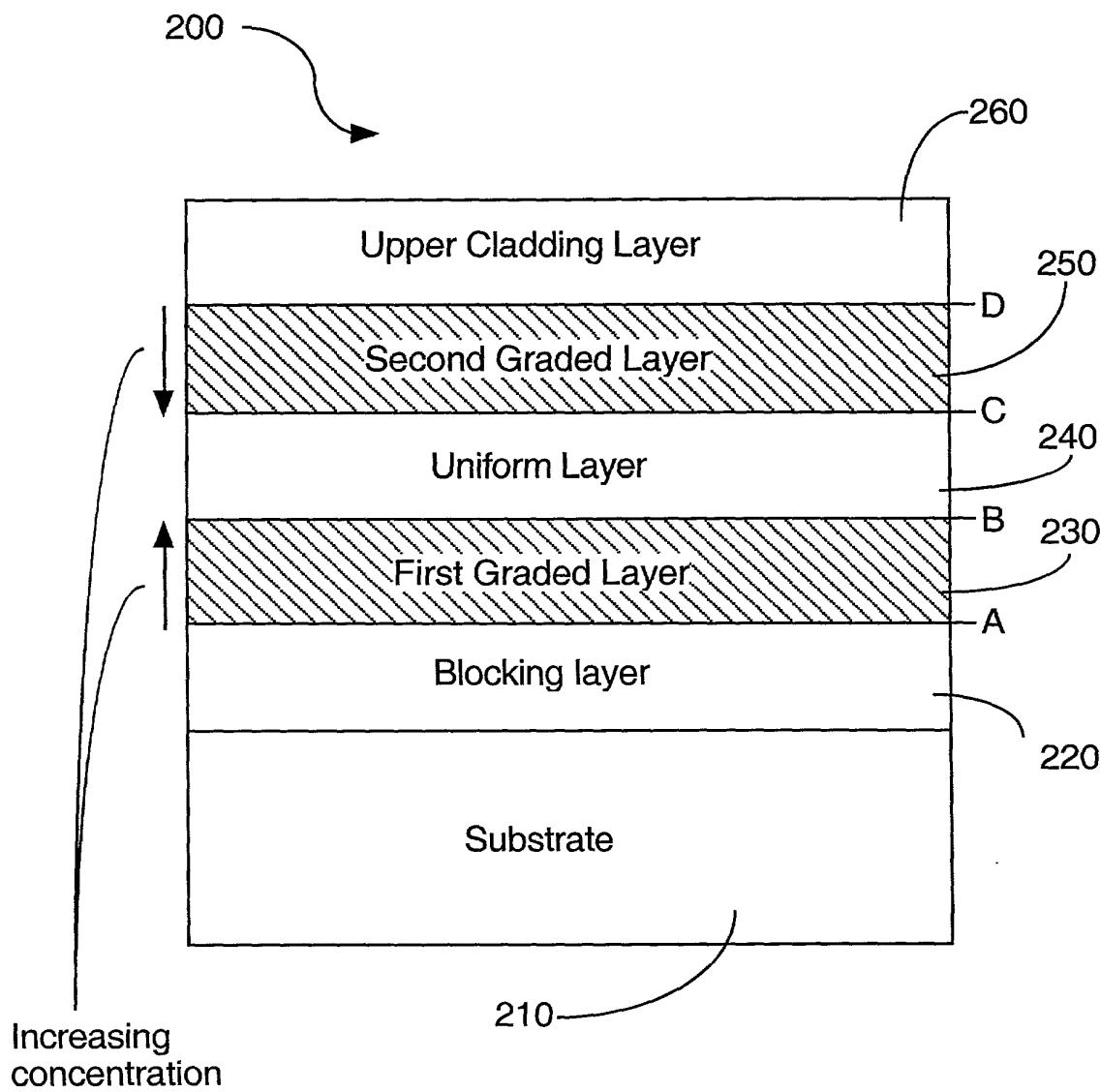
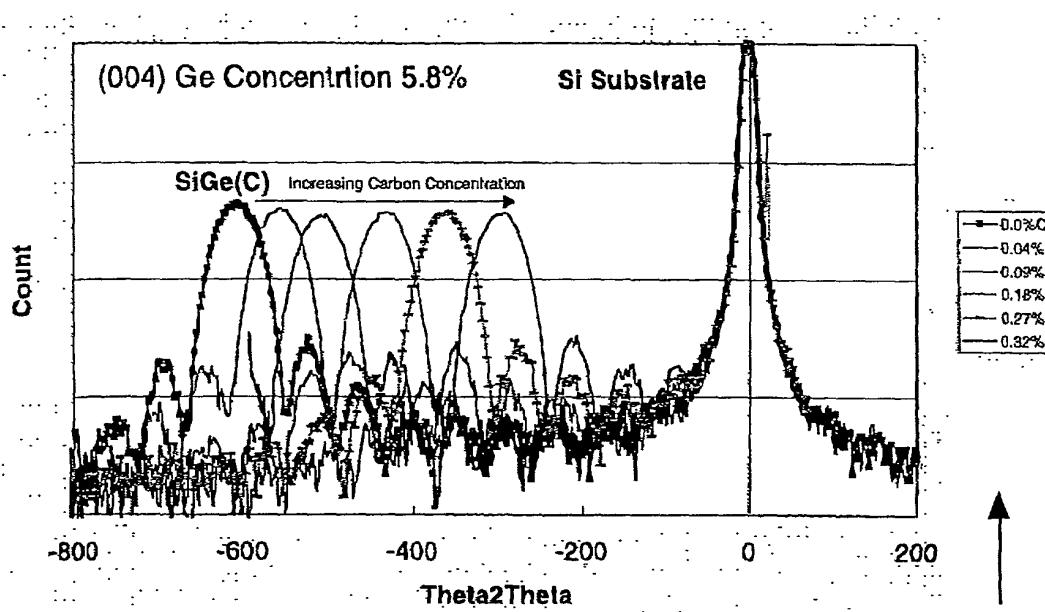


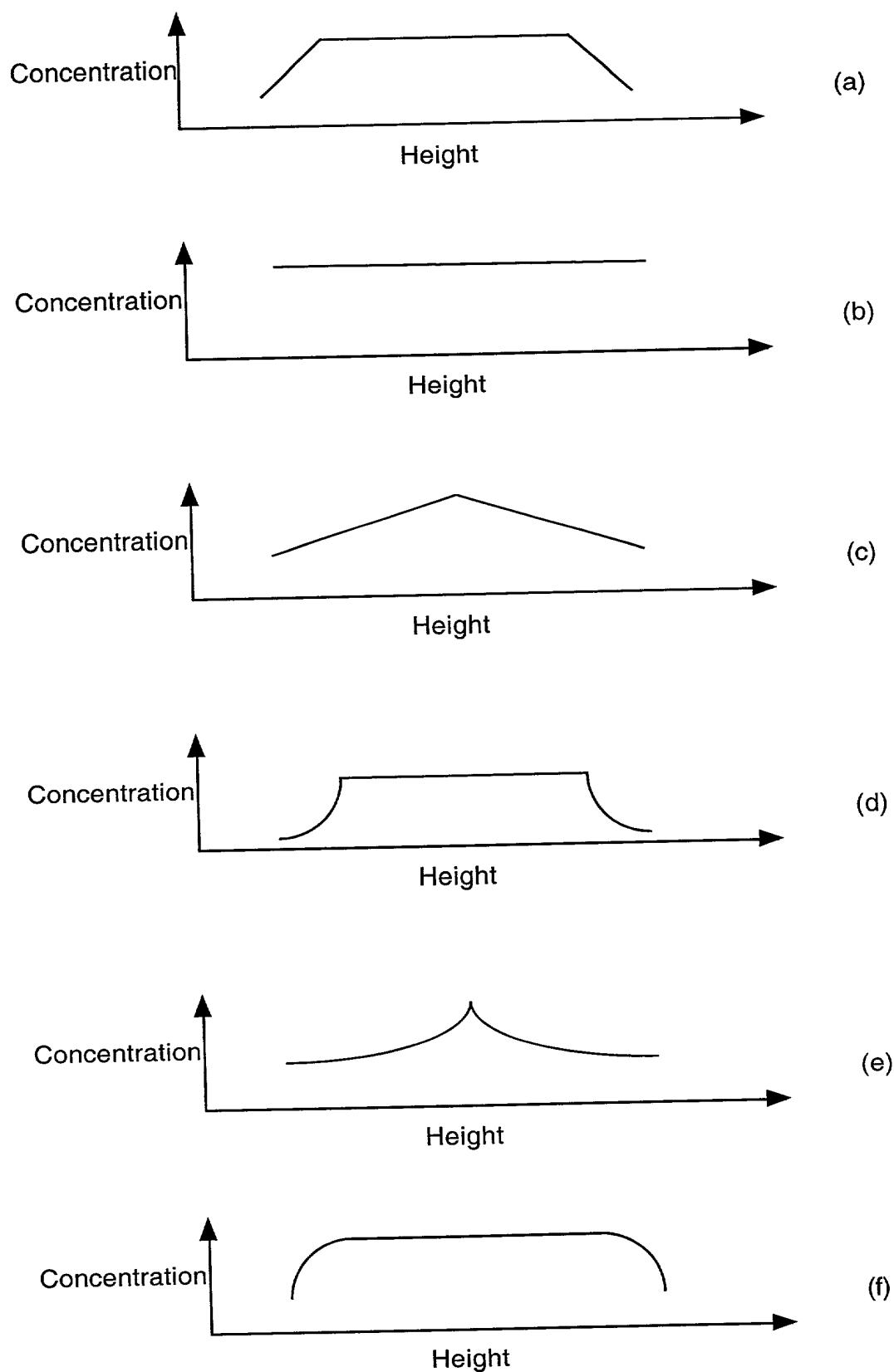
Figure 2A

X-Ray Photoelctron Deffraction Graph  
of a Si Substrate and SiGeC Layers with  
Different C Concentrations



Approximate  
concentrations  
of substitutional  
carbon atoms

Figure 2B



# Figure 3

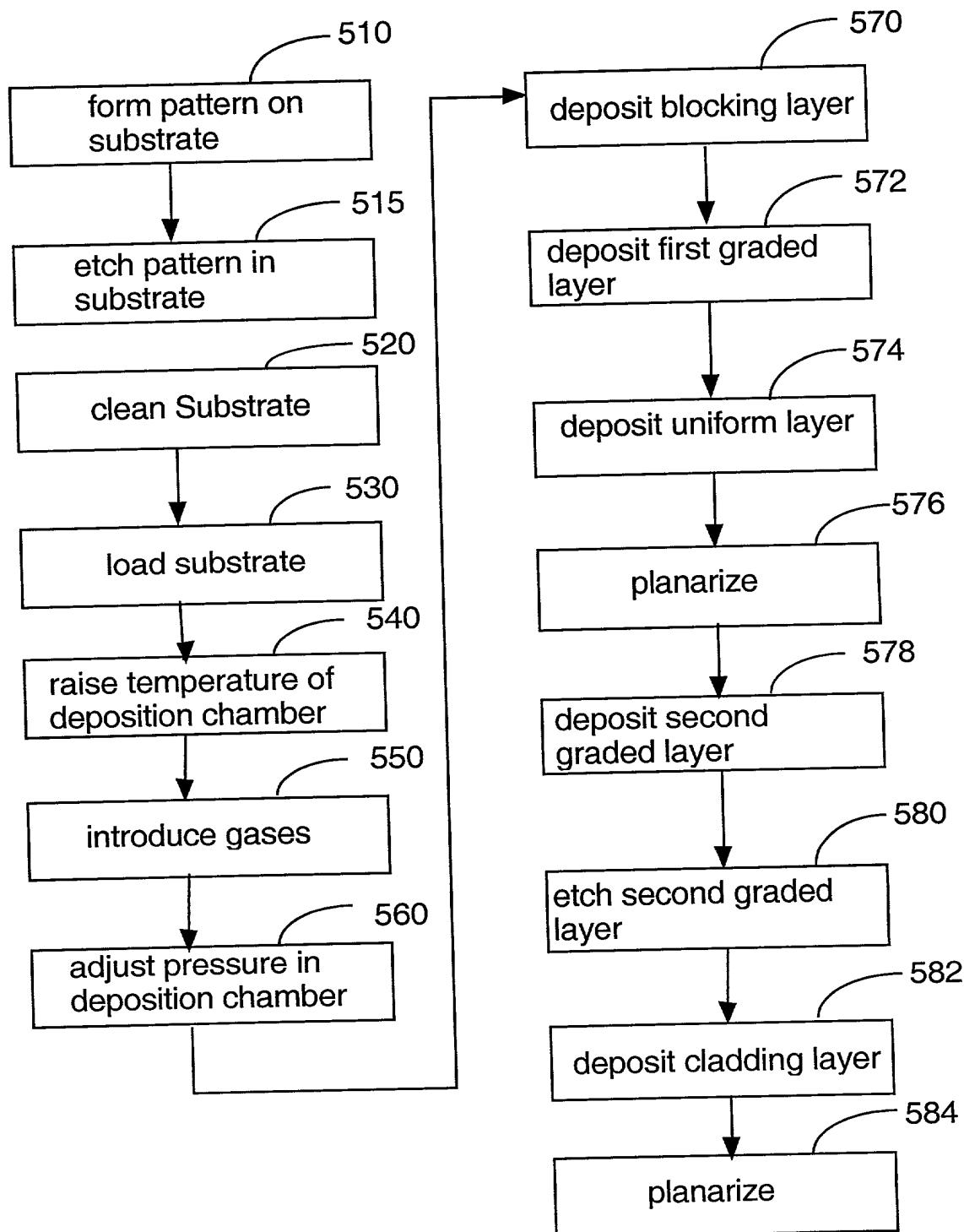


Figure 4

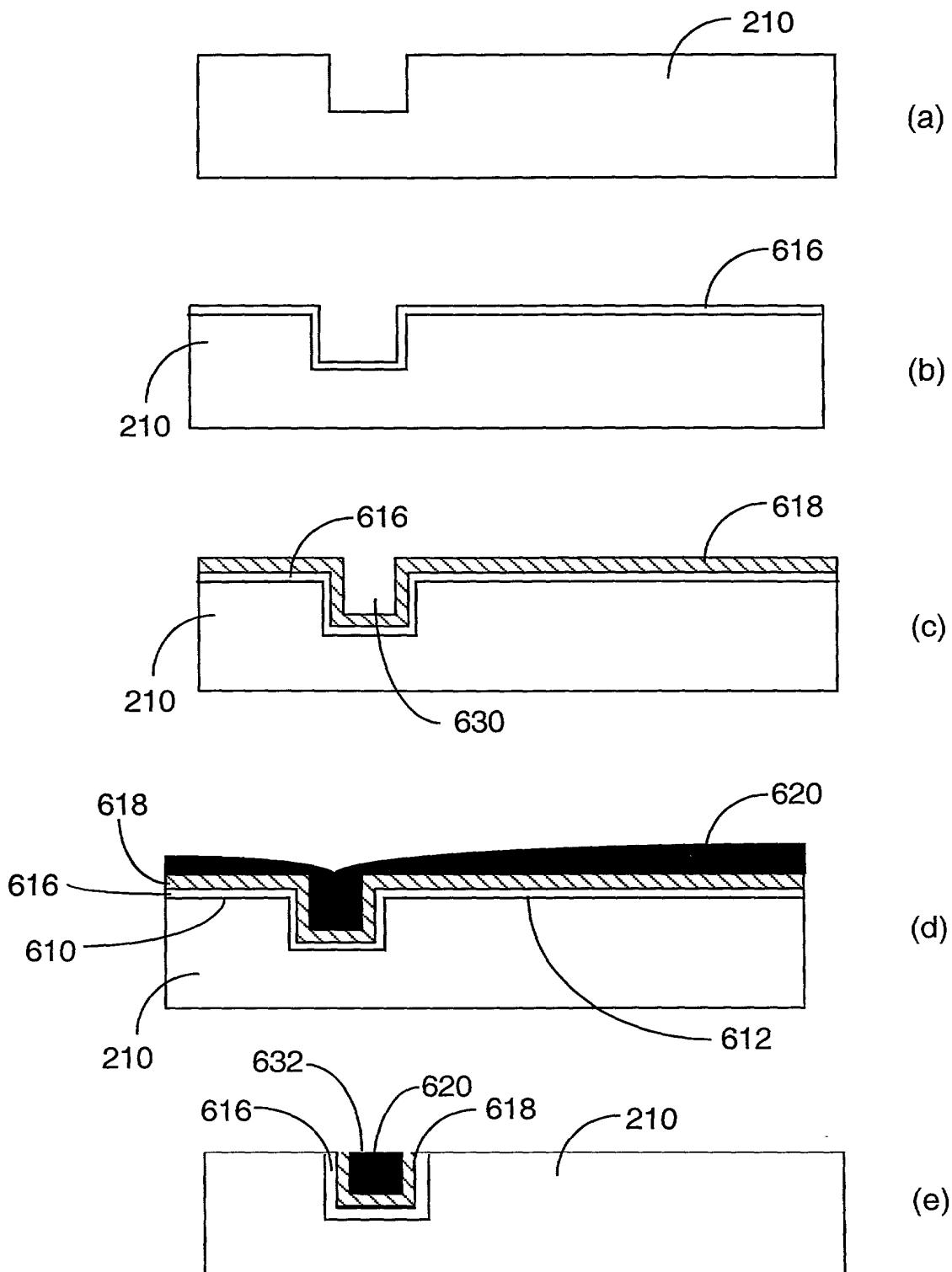


Figure 5

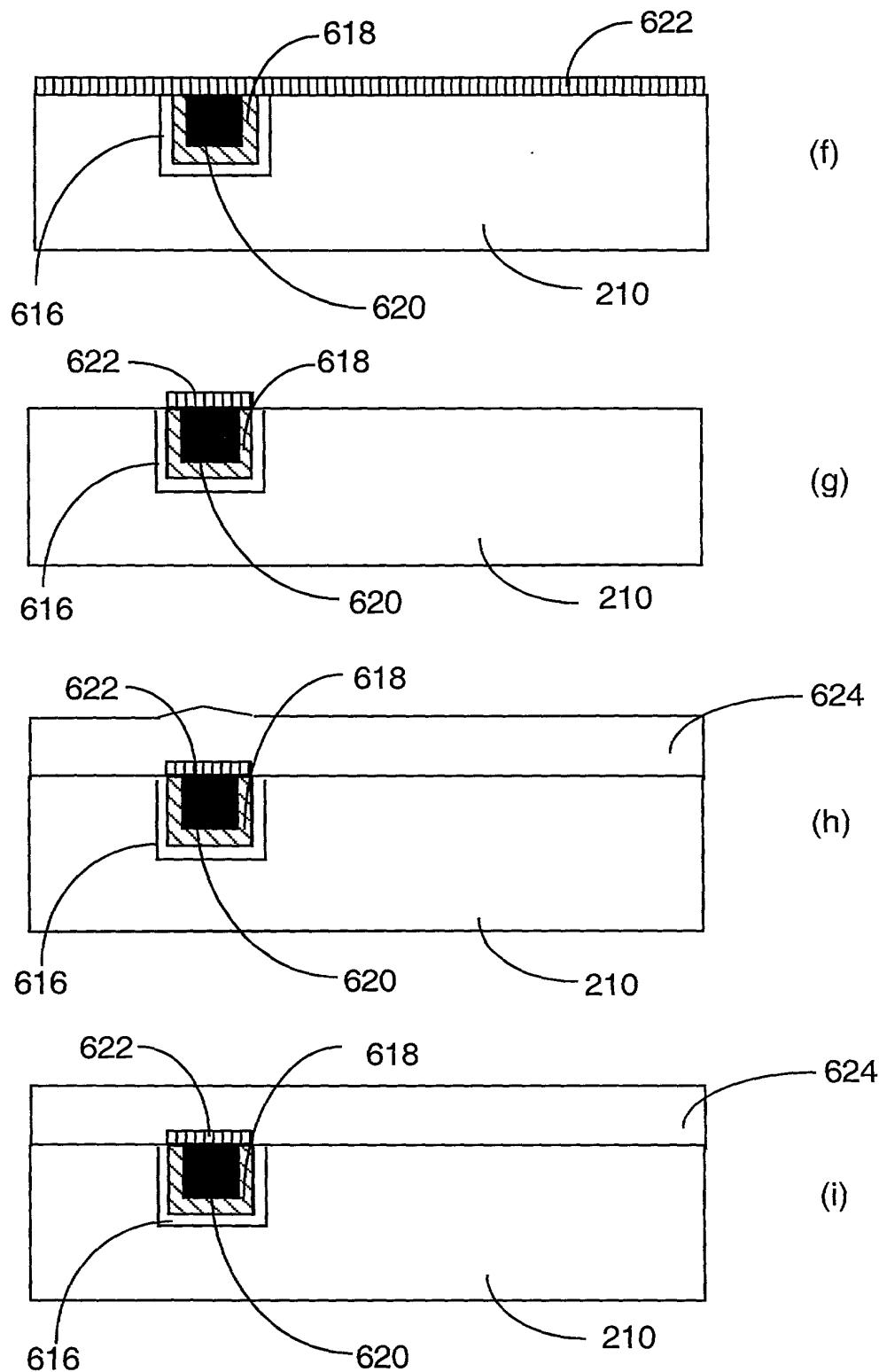


Figure 5

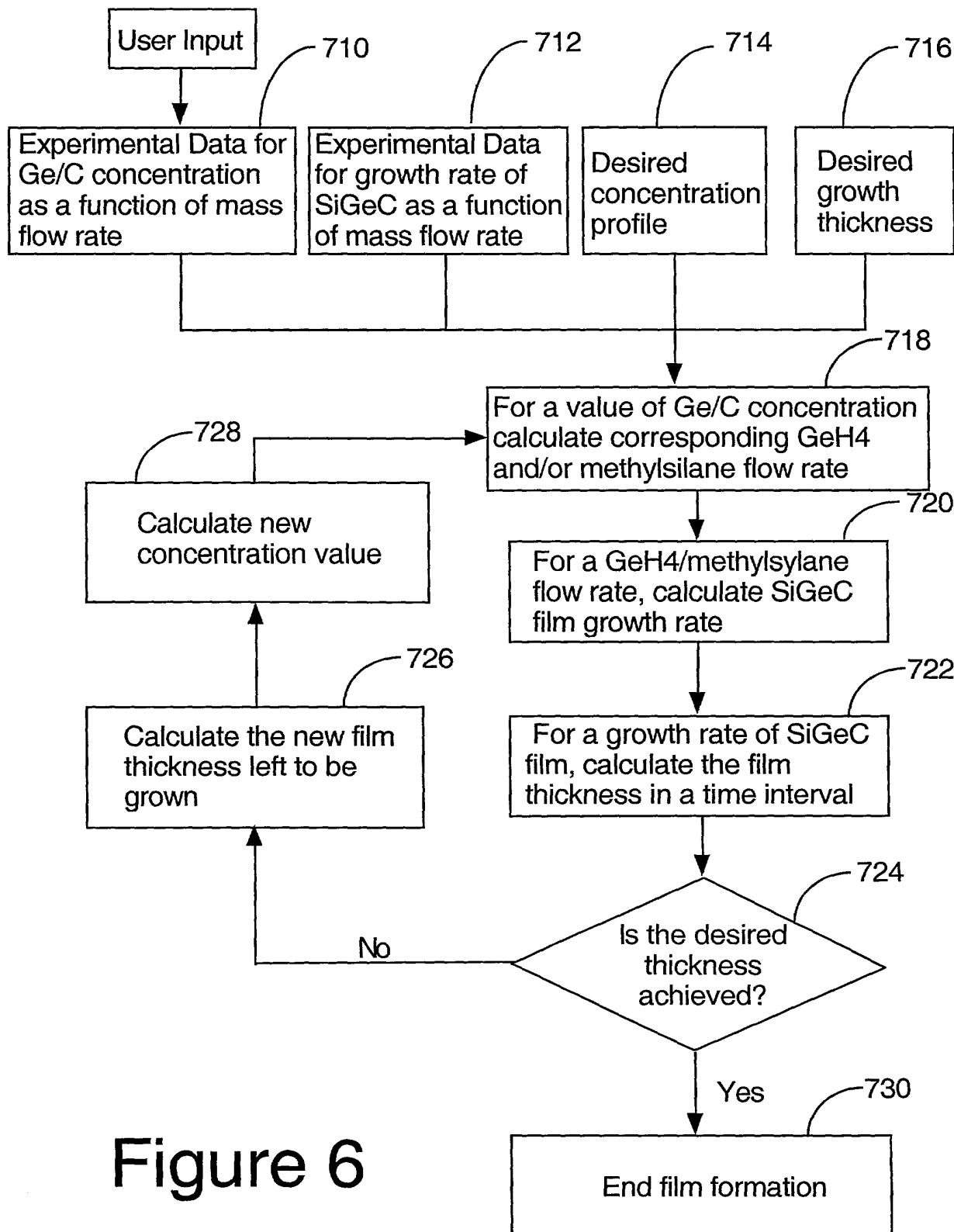
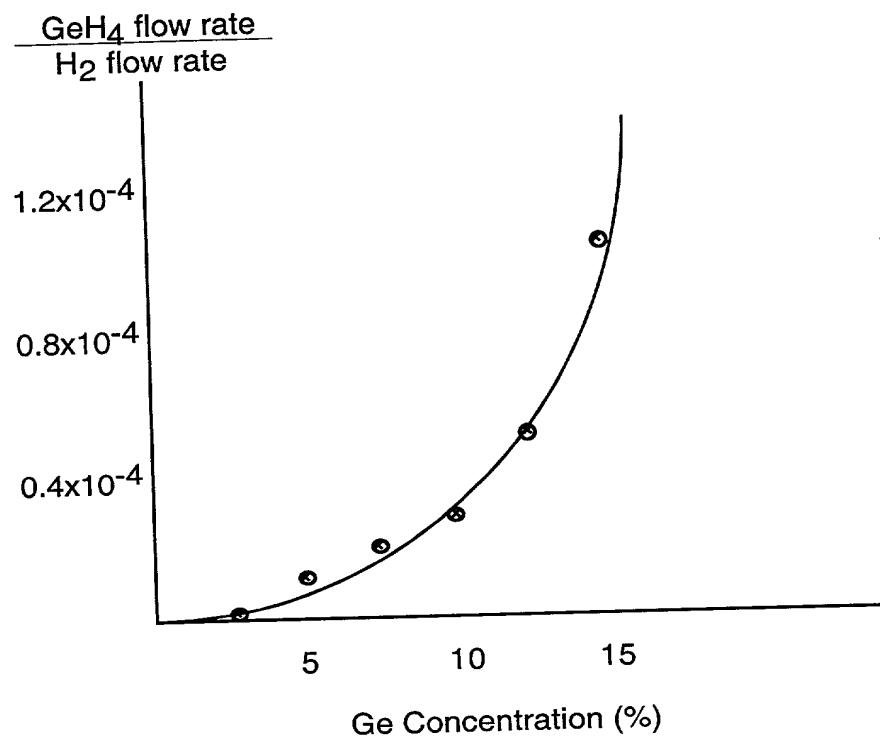
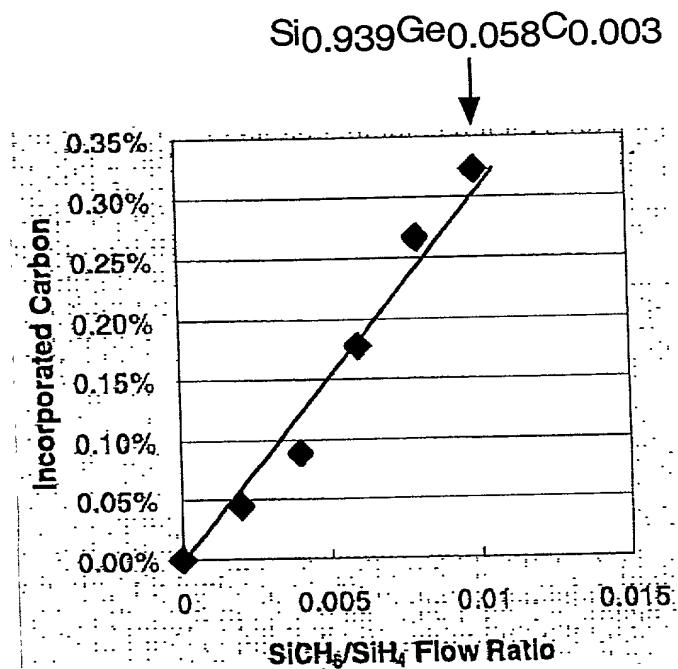


Figure 6



## Figure 7A



## Figure 7B

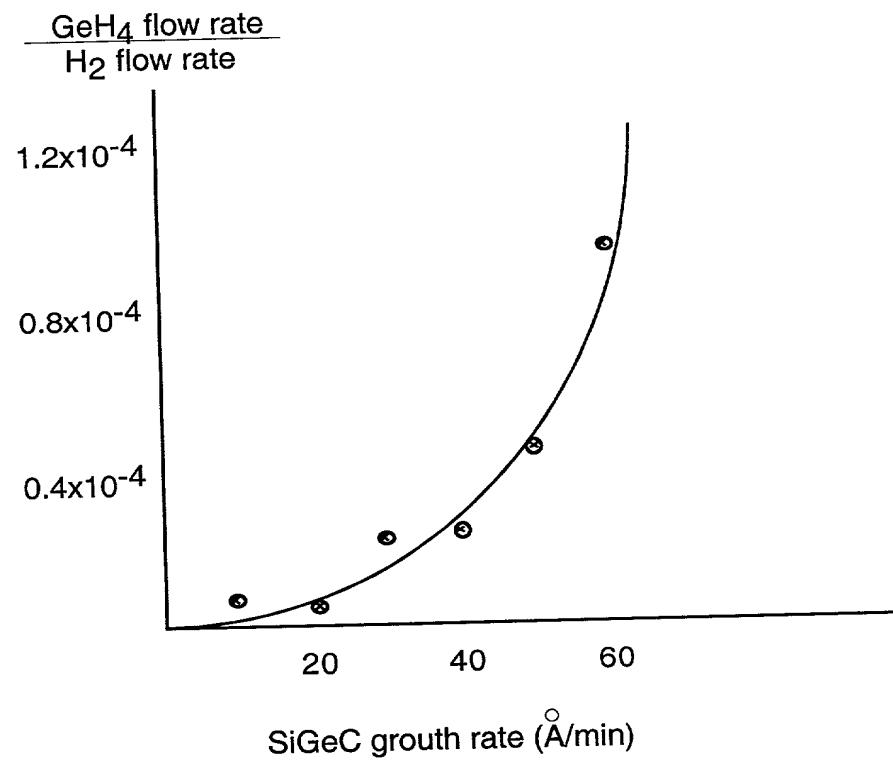
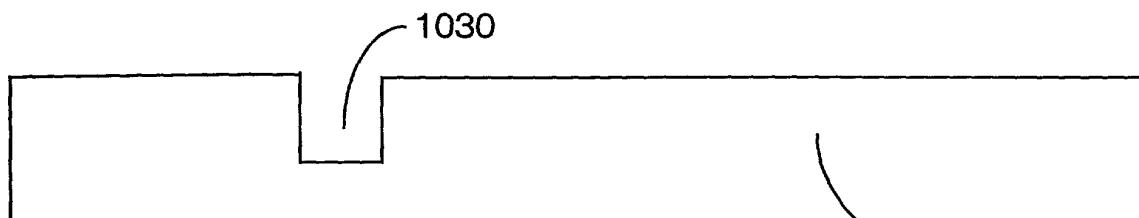
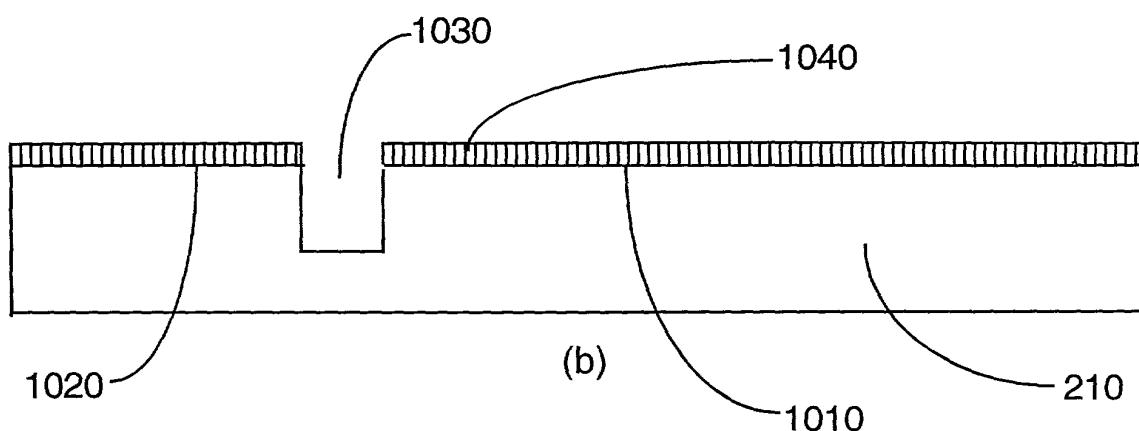


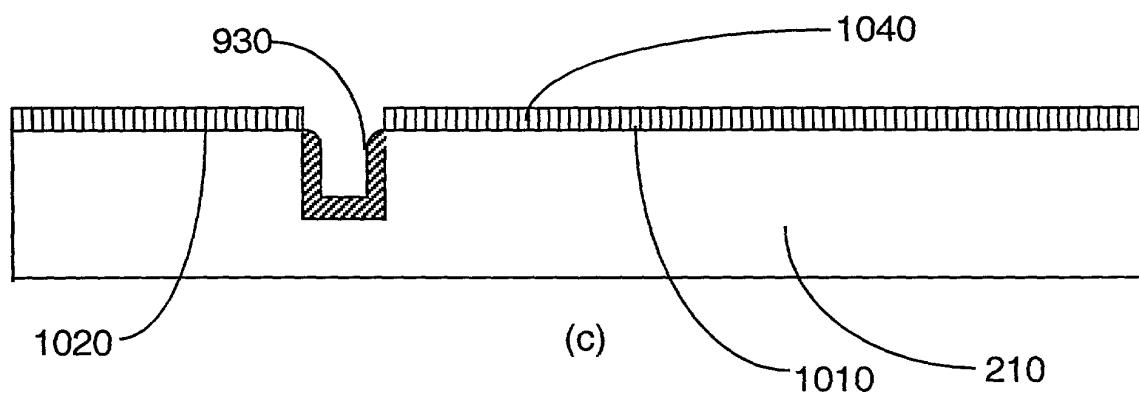
Figure 8



(a)



(b)



(c)

Figure 9

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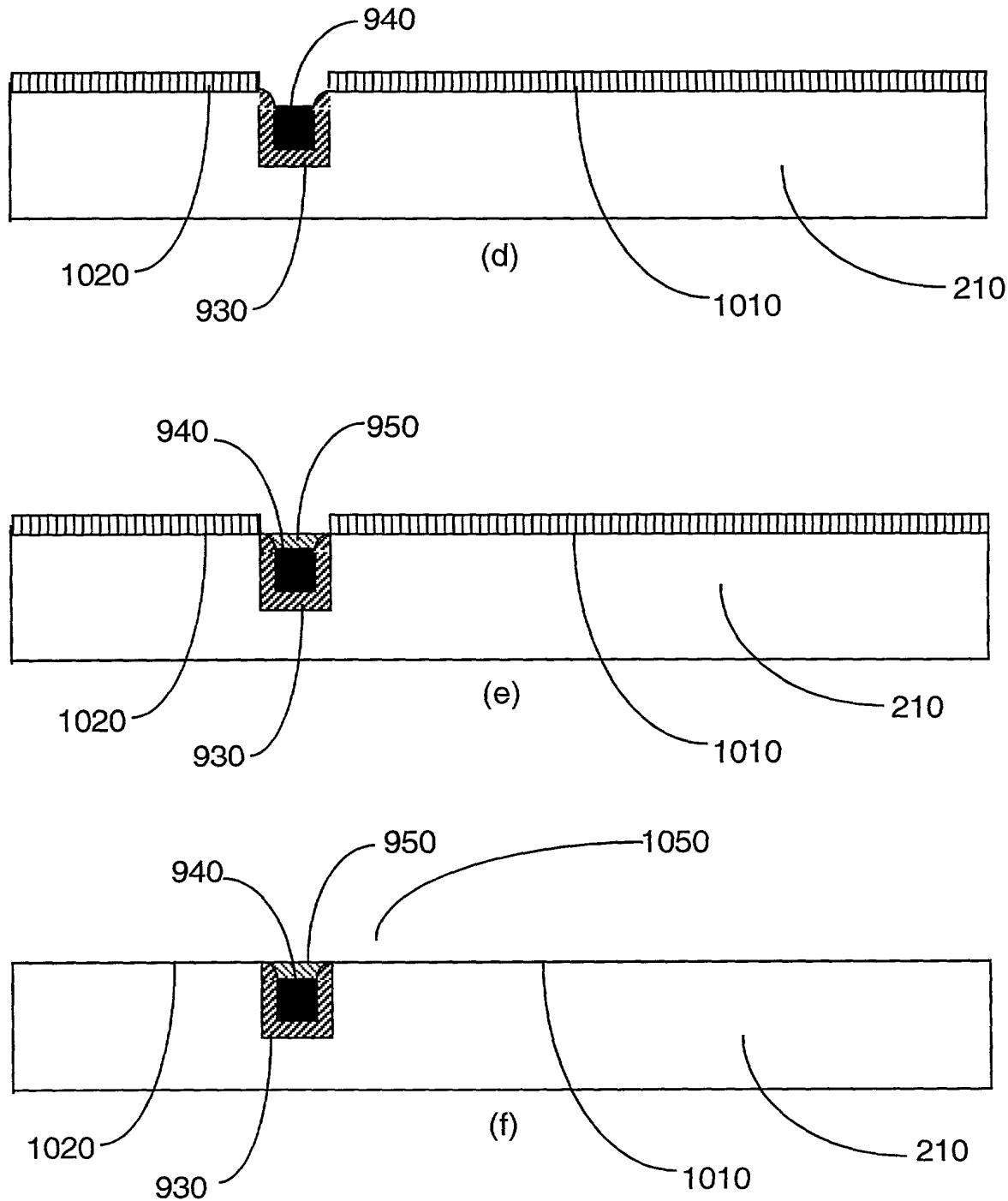


Figure 9

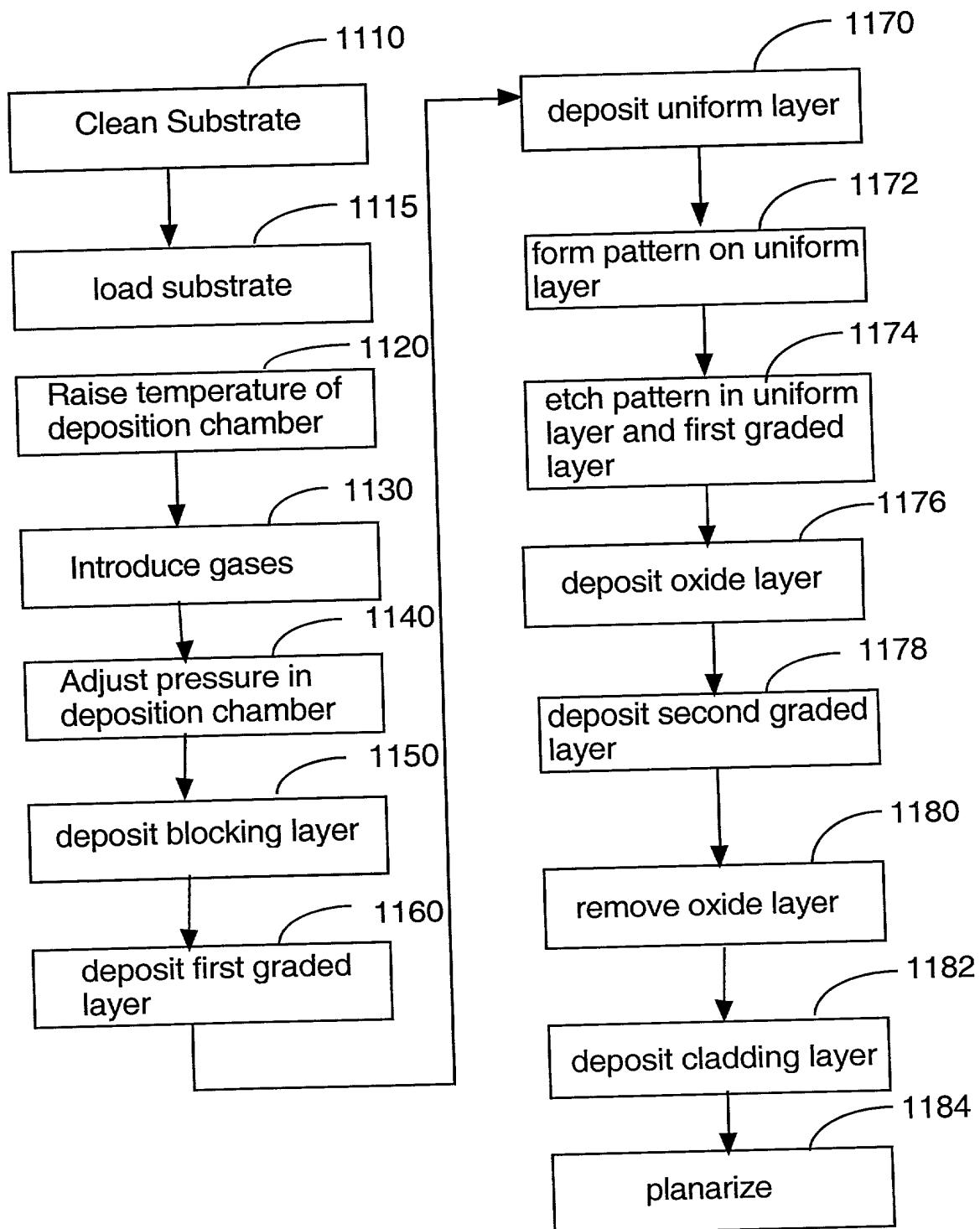


Figure 10

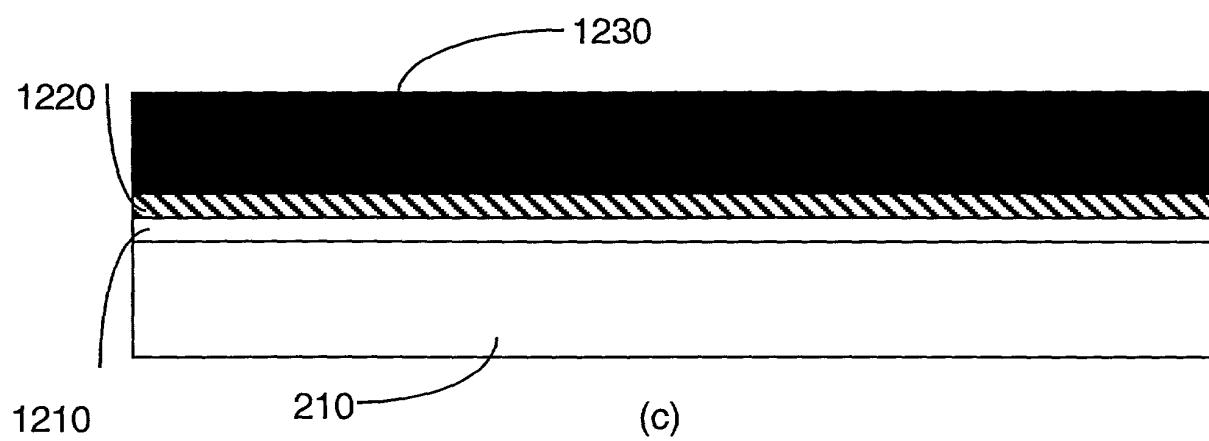
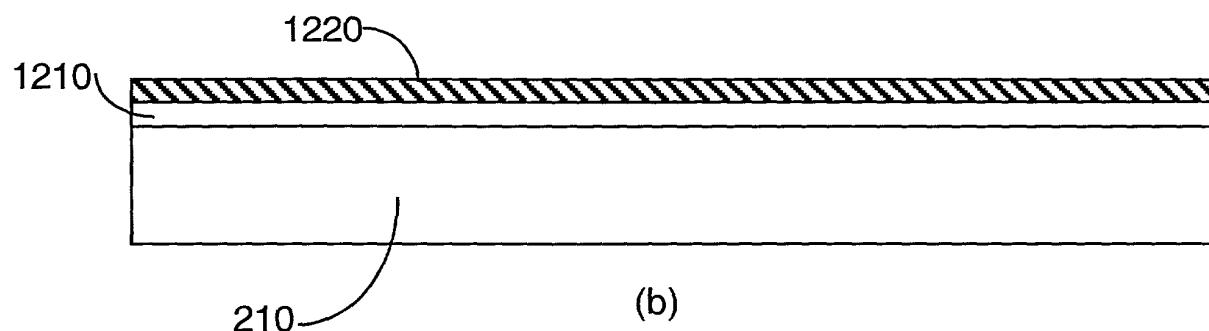
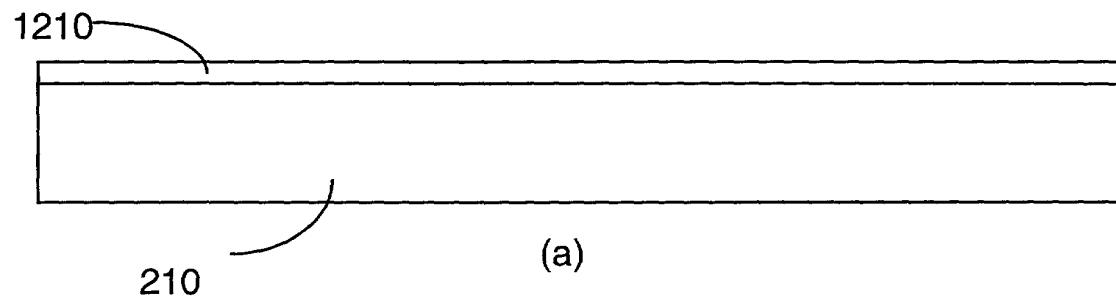


Figure 11

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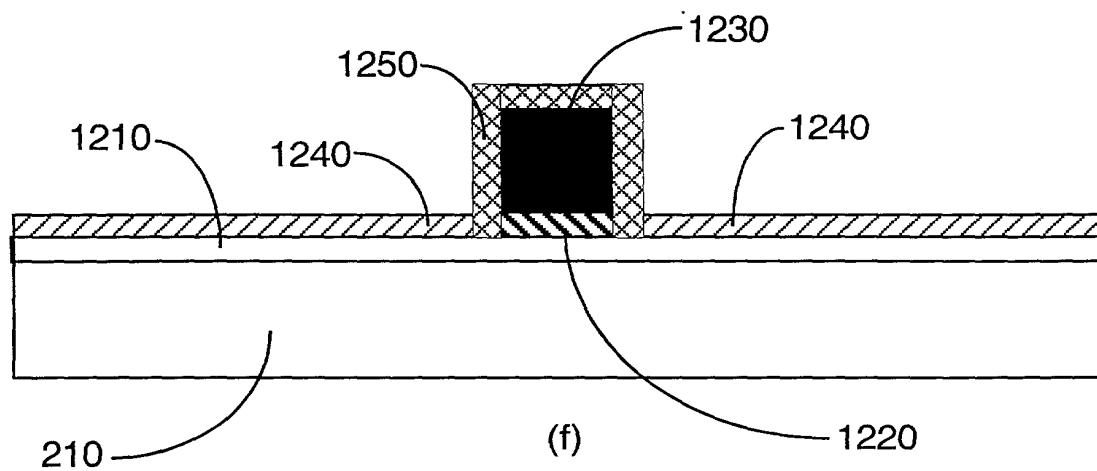
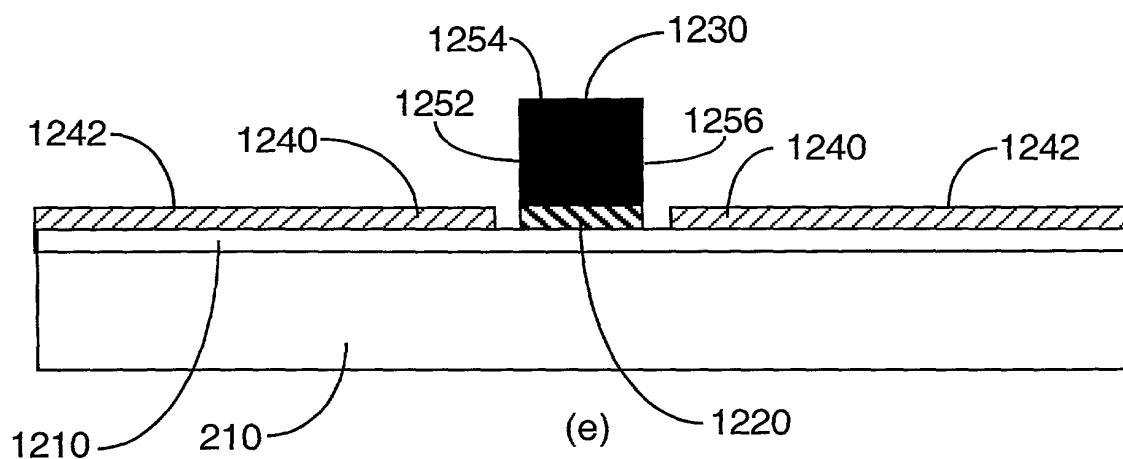
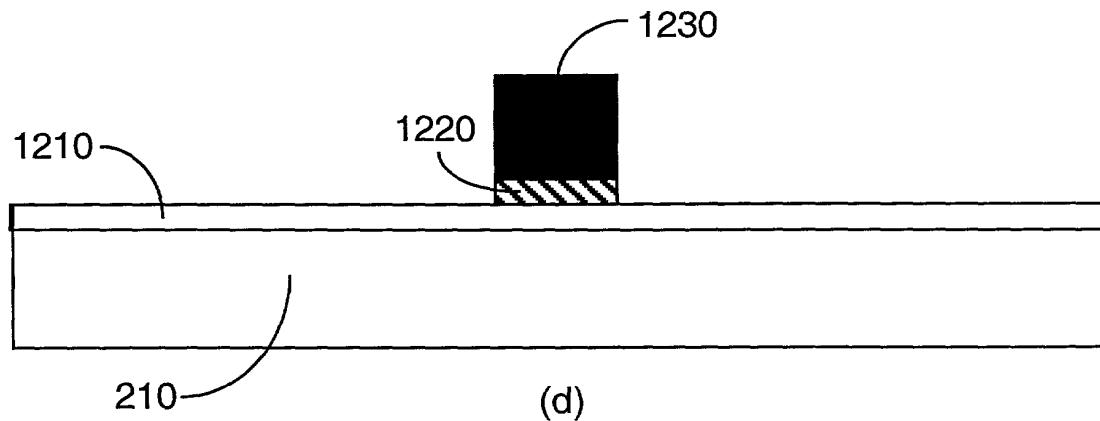
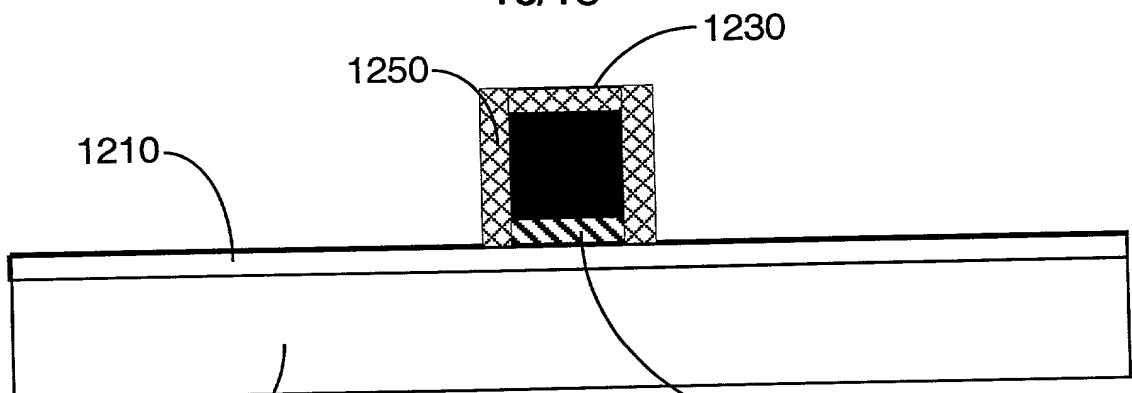
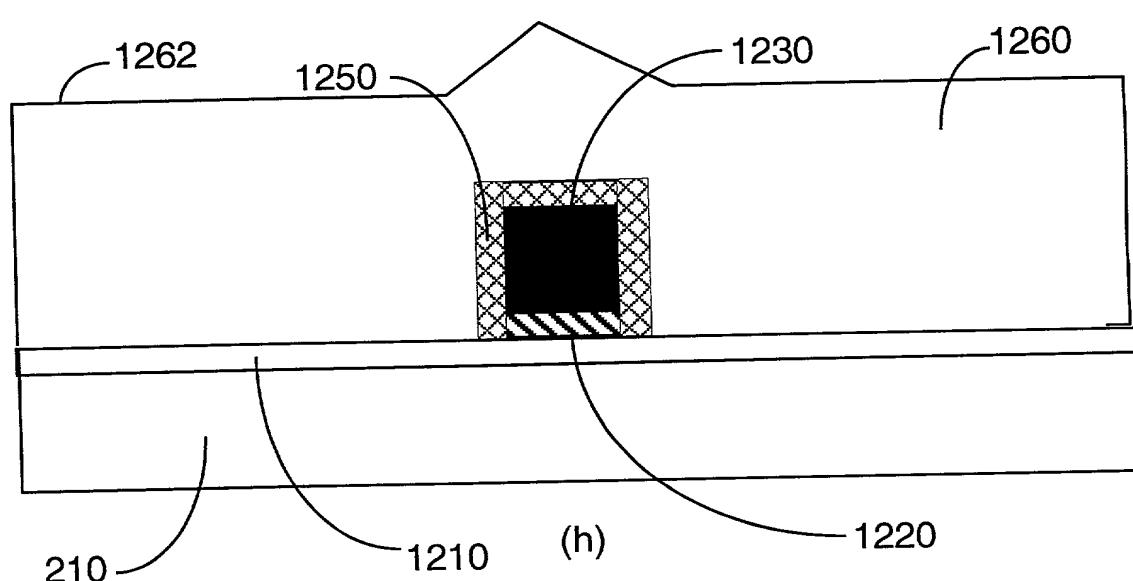


Figure 11

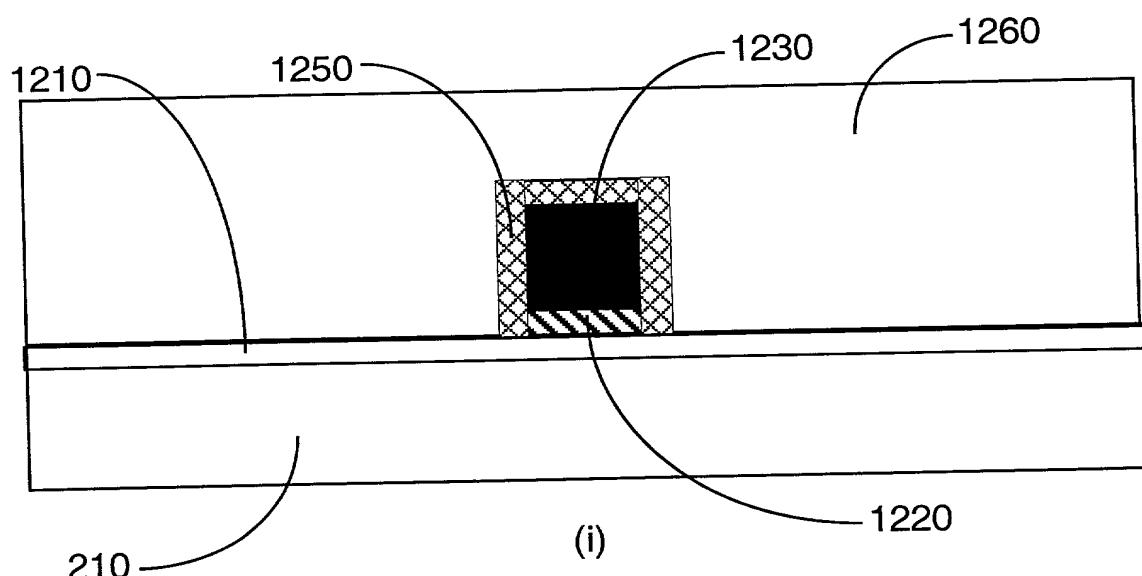
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(g)



(h)



(i)

**Figure 11**

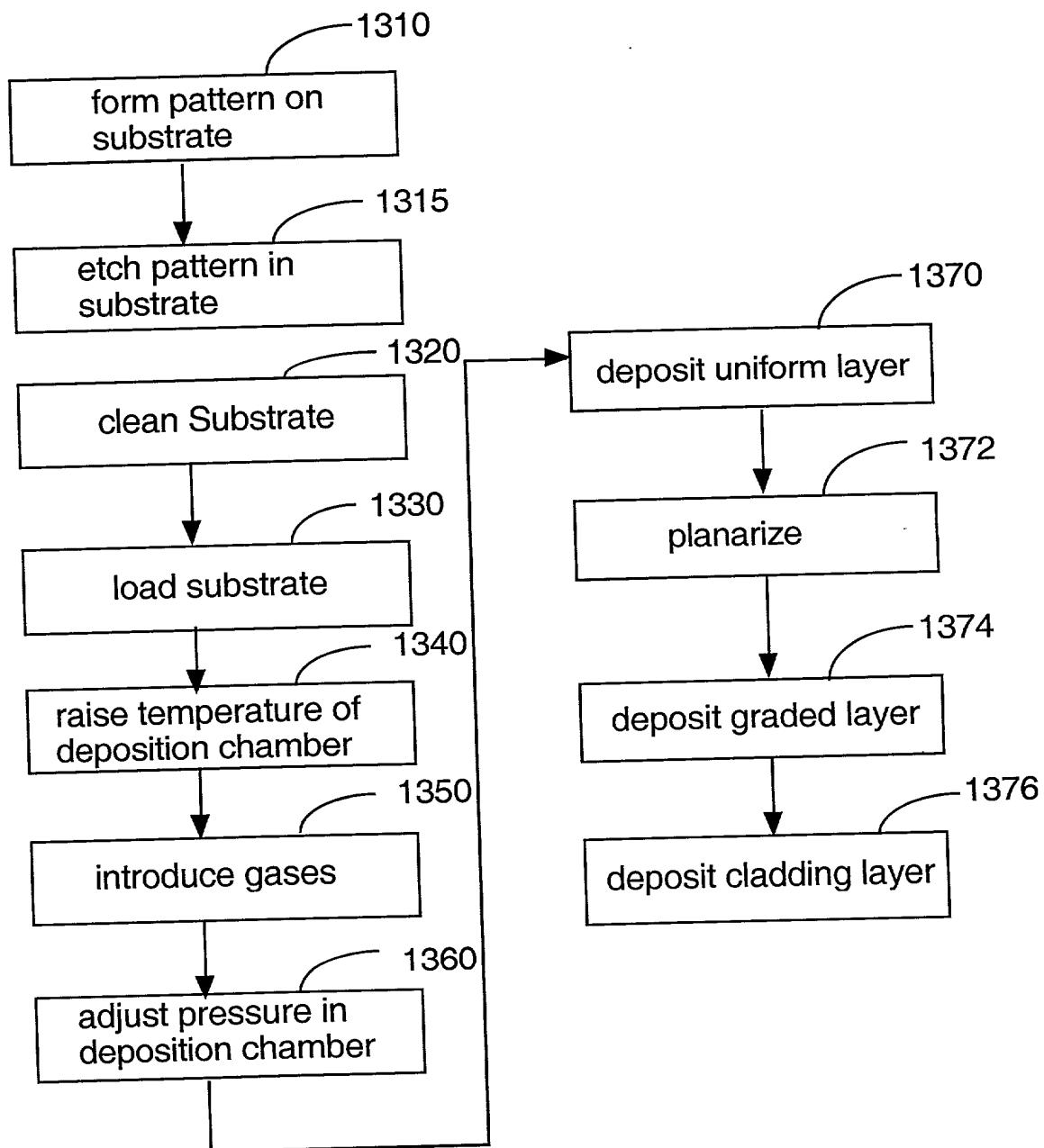


Figure 12

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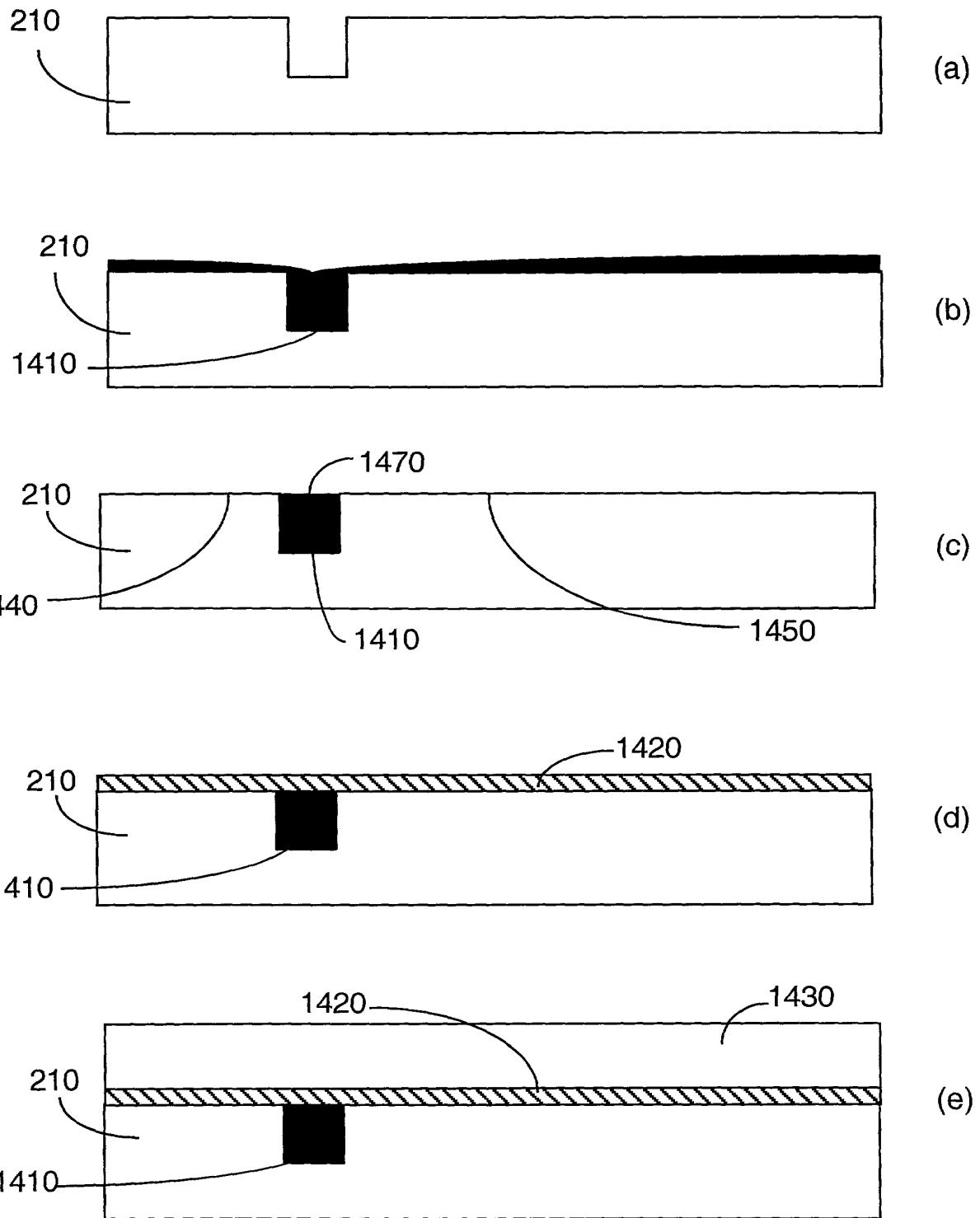


Figure 13